Issue Classification

CLASS

375

CLASS

ORIGINAL

CROSS REFERENCE(S)

296

SUBCLASS (ONE SUBCLASS PER BLOCK)

10627881

Examiner

Lee, Siu M

SUBCLASS

Applicant(s)/Patent Under Reexamination

NON-CLAIMED

SAED, ARYAN

INTERNATIONAL CLASSIFICATION

Art Unit

2611

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CLAIMED

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